Performance Optimized Expectation Conditional Maximization Algorithms for Nonhomogeneous Poisson Process Software Reliability Models

Vidhyashree Nagaraju, *Member, IEEE*, Lance Fiondella, *Member, IEEE*, Panlop Zeephongsekul, *Member, IEEE*, Chathuri L. Jayasinghe, and Thierry Wandji, *Member, IEEE*

Abstract-Nonhomogeneous Poisson process (NHPP) and software reliability growth models (SRGM) are a popular approach to estimate useful metrics such as the number of faults remaining, failure rate, and reliability, which is defined as the probability of failure free operation in a specified environment for a specified period of time. We propose performance-optimized expectation conditional maximization (ECM) algorithms for NHPP SRGM. In contrast to the expectation maximization (EM) algorithm, the ECM algorithm reduces the maximum-likelihood estimation process to multiple simpler conditional maximization (CM)-steps. The advantage of these CM-steps is that they only need to consider one variable at a time, enabling implicit solutions to update rules when a closed form equation is not available for a model parameter. We compare the performance of our ECM algorithms to previous EM and ECM algorithms on many datasets from the research literature. Our results indicate that our ECM algorithms achieve two orders of magnitude speed up over the EM and ECM algorithms of [1] when their experimental methodology is considered and three orders of magnitude when knowledge of the maximum-likelihood estimation is removed, whereas our approach is as much as 60 times faster than the EM algorithms of [2]. We subsequently propose a two-stage algorithm to further accelerate performance.

Index Terms—Expectation conditional maximization (ECM) algorithm, nonhomogeneous Poisson process (NHPP), software reliability, software reliability growth model, two-stage algorithm.

NOMENCLATURE

Acronyms

EM Expectation-maximization.

Manuscript received May 10, 2016; revised November 3, 2016 and January 7, 2017; accepted June 12, 2017. Date of publication July 6, 2017; date of current version August 30, 2017. This work was supported in part by the Naval Air Systems Command through the Systems Engineering Research Center, a Department of Defense University Affiliated Research Center under Research Task 139: Software Reliability Modeling and in part by the National Science Foundation under Grant 1526128. Associate Editor: Z. Chen. (Corresponding author: Lance Fiondella.)

V. Nagaraju and L. Fiondella are with the Department of Electrical and Computer Engineering, University of Massachusetts, Dartmouth, MA 02747 USA (e-mail: ynagaraju@umassd.edu; lfiondella@umassd.edu).

P. Zeephongsekul is with the School of Mathematical and Geospatial Sciences, RMIT University, Melbourne, Vic 3000, Australia (e-mail: panlopz@rmit.edu.au)

C. L. Jayasinghe is with the Department of Statistics, Faculty of Applied Sciences, University of Sri Jayewardenepura, Nugegoda 10250. Sri Lanka (e-mail: chathuri@sjp.ac.lk).

T. Wandji is with the Naval Air Systems Command, Patuxent River, MD 20670 USA (e-mail: ketchiozo.wandji@navy.mil).

Digital Object Identifier 10.1109/TR.2017.2716419

ECM Expectation conditional maximization.

DSS Delayed S-shaped model.

CDF Cumulative distribution function.

LL Log-likelihood function.

RLL Reduced log-likelihood function.
MLE Maximum-likelihood estimation.

MVF Mean value function.

NHPP Nonhomogeneous Poisson process. SRGM Software reliability growth models.

GO Goel-Okumoto model.

ISS Inflexion S-shaped model.

Notation

- m(t) MVF of NHPP.
- $\lambda(t)$ Instantaneous failure rate.
- F(t) Cumulative distribution function of software fault detection process.
- a Number of latent faults at start of testing.
- b Scale parameter of Weibull SRGM testing.
- c Shape parameter of Weibull SRGM testing.
- ϕ Rate at which bathtub transitions, from second to final phase.
- Ψ Inflexion parameter.
- r Inflexion rate.
- Γ Gamma function.
- F Polygamma function.
- G MeijerG function.
- N Total number of faults.
- Observed number of faults.
- m Unobserved number of faults.
- T Vector of failure times.
- t_i Time of the *i*th failure.
- t_n nth observed failure.
- $t_{\rm obs}$ Time at which testing stopped.
- s Mission time.
- x Observed data.
- z Unobserved data.
- Θ Vector of model parameters.
- p Number of model parameters.
- Δ Vector of conditional maximization steps.
- δ Subvector of conditional maximization steps.
- $\Theta_i^{(j)}$ ith model parameter in the jth iteration